

Electronic Supplementary Information

Ultrathin $\text{Bi}_2\text{O}_2\text{S}$ Nanosheets Near-Infrared Photodetectors

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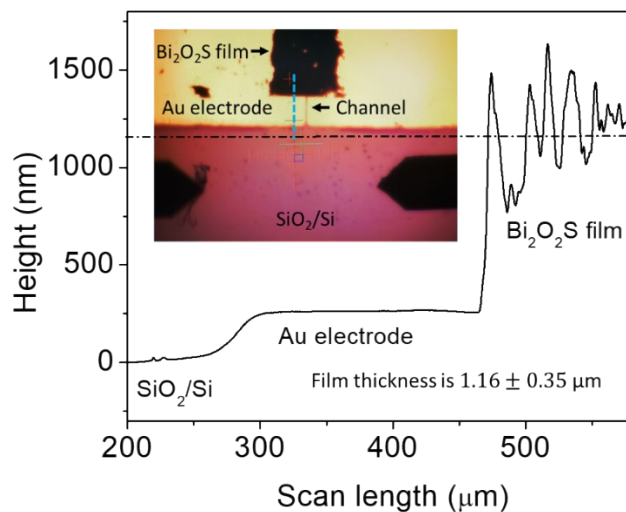


Fig. S1. $\text{Bi}_2\text{O}_2\text{S}$ film thickness measurement using a profilometer. The scan direction and length are shown with a blue dotted line. Inset depicts the optical image of the device collected during profilometer measurement.

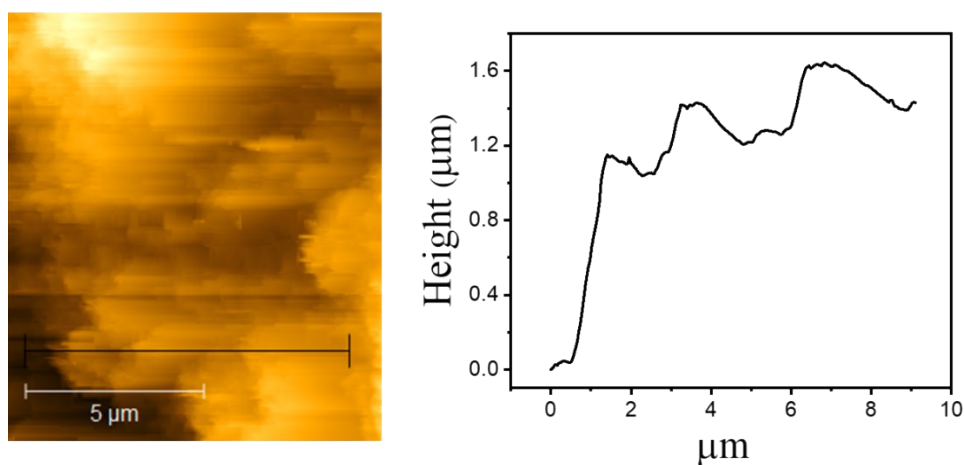


Fig. S2. $\text{Bi}_2\text{O}_2\text{S}$ film thickness measurement by AFM with corresponding thickness profile.

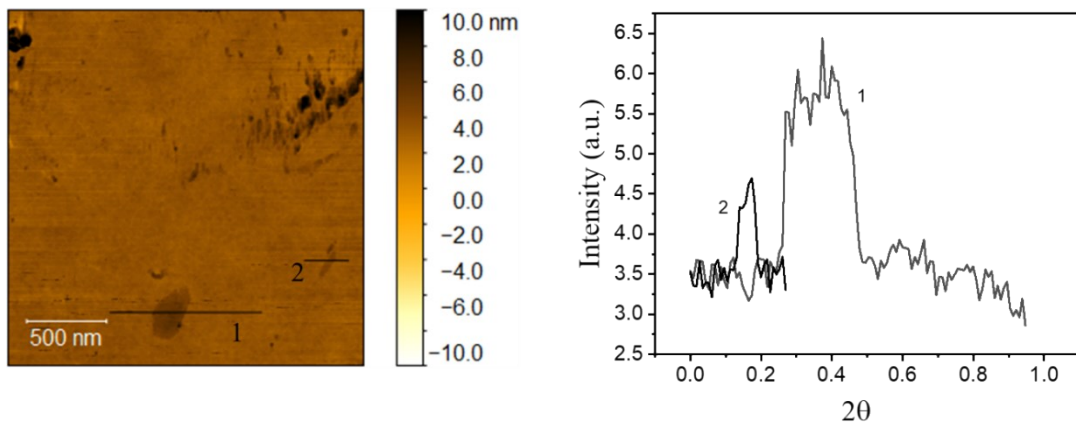


Fig. S3. AFM of the Bi₂O₂S nanosheets with height profiles taken at two different locations.